3.3 V, 100 MHz LVPECL Clock Oscillator

The NBXSBA010, single frequency, crystal oscillator (XO) is designed to meet today's requirements for 3.3 V LVPECL clock generation applications. The device uses a high Q fundamental crystal and Phase Lock Loop (PLL) multiplier to provide 100 MHz, ultra low jitter and phase noise LVPECL differential output.

This device is a member of ON Semiconductor's PureEdge[™] clock family that provides accurate and precision clock solutions.

Available in 5 mm x 7 mm SMD (CLCC) package on 16 mm tape and reel in quantities of 1,000.

Features

- LVPECL Differential Output
- Uses High Q Fundamental Mode Crystal and PLL Multiplier
- Ultra Low Jitter and Phase Noise 0.4 ps (12 kHz 20 MHz)
- Output Frequency 100 MHz
- Hermetically Sealed Ceramic SMD Package
- RoHS Compliant
- Operating Range 3.3 V ±10%
- Total Frequency Stability ± 50 PPM
- This is a Pb–Free Device

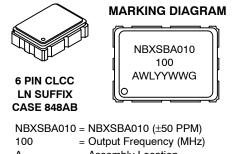
Applications

- Infiniband
- PCIe
- Host Bus Adapter
- RAID Controller



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100	= Output Frequency (MHz)
А	= Assembly Location
WL	= Wafer Lot
YY	= Year
WW	= Work Week
G	= Pb-Free Package

ORDERING INFORMATION

Device	Package	Shipping†
NBXSBA010LN1TAG	CLCC-6 (Pb-Free)	
NBXSBA010LNHTAG	CLCC-6 (Pb-Free)	100/Tape & Reel

+ For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

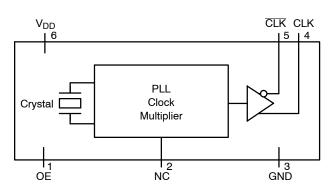


Figure 1. Simplified Logic Diagram

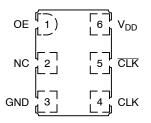


Figure 2. Pin Connections (Top View)

Table 1. PIN DESCRIPTION

Pin No.	Symbol	I/O	Description
1	OE	LVTTL/LVCMOS Control Input	Output Enable Pin. When left floating pin defaults to logic HIGH and output is active. See OE pin description Table 2.
2	NC	N/A	No Connect.
3	GND	Power Supply	Ground 0 V
4	CLK	LVPECL Output	Non–Inverted Clock Output. Typically loaded with 50 Ω receiver termination resistor to V_{TT} = V_{DD} – 2 V.
5	CLK	LVPECL Output	Inverted Clock Output. Typically loaded with 50 Ω receiver termination resistor to V_{TT} = V_{DD} – 2 V.
6	V _{DD}	Power Supply	Positive power supply voltage. Voltage should not exceed 3.3 V $\pm 10\%.$

Table 2. OUTPUT ENABLE TRI-STATE FUNCTION

OE Pin	Output Pins
Open	Active
HIGH Level	Active
LOW Level	High Z

Table 3. ATTRIBUTES

Characteristic		Value	
Internal Default State Resistor		170 kΩ	
ESD Protection Human Body Model Machine Model		2 kV 200 V	
Meets or Exceeds JE	DEC Standard EIA/JESD78	IC Latchup Test	

1. For additional Moisture Sensitivity information, refer to Application Note AND8003/D.

Table 4. MAXIMUM RATINGS

Symbol	Parameter	Condition 1	Condition 2	Rating	Units
V _{DD}	Positive Power Supply	GND = 0 V		4.6	V
l _{out}	LVPECL Output Current	Continuous Surge		25 50	mA
Τ _Α	Operating Temperature Range			-40 to +85	°C
T _{stg}	Storage Temperature Range			-55 to +120	°C
T _{sol}	Wave Solder	See Figure 5		260	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

Symbol	Characteristic		Conditions	Min.	Тур.	Max.	Units
I _{DD}	Power Supply Current				75	100	mA
VIH	OE Input HIGH Voltage			2000		V _{DD}	mV
V _{IL}	OE Input LOW Voltage			GND – 300		800	mV
Ι _{ΙΗ}	Input HIGH Current	OE FSEL		-100 -100		+100 +100	μΑ
I _{IL}	Input LOW Current	OE FSEL		-100 -100		+100 +100	μΑ
V _{OH}	Output HIGH Voltage		V _{DD} = 3.3 V	V _{DD} -1195 2105		V _{DD} -945 2355	mV
V _{OL}	Output LOW Voltage		V _{DD} = 3.3 V	V _{DD} -1945 1355		V _{DD} -1600 1700	mV
V _{OUTPP}	Output Voltage Amplitude				700		mV

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

2. Measurement taken with outputs terminated with 50 Ω to V_{DD} – 2.0 V. See Figure 4.

Symbol	Characteristic	Conditions	Min.	Тур.	Max.	Units
f _{CLKOUT}	Output Clock Frequency			100		MHz
Δf	Frequency Stability – NBXSBA010	(Note 4)			±50	ppm
Φ_{NOISE}	Phase-Noise Performance	100 Hz of Carrier		-109		dBc/Hz
	f _{CLKout} = 100 MHz (See Figure 3)	1 kHz of Carrier		-125		dBc/Hz
		10 kHz of Carrier		-132		dBc/Hz
		100 kHz of Carrier		-132		dBc/Hz
		1 MHz of Carrier		-141		dBc/Hz
		10 MHz of Carrier		-161		dBc/Hz
t _{jit} (Φ)	RMS Phase Jitter	12 kHz to 20 MHz		0.4	0.9	ps
t _{jitter}	Cycle to Cycle, RMS	1000 Cycles		1.5	8	ps
	Cycle to Cycle, Peak-to-Peak	1000 Cycles		15	30	ps
	Period, RMS	10,000 Cycles		1	4	ps
	Period, Peak-to-Peak	10,000 Cycles		10	20	ps
t _{OE/OD}	Output Enable/Disable Time				200	ns
^t DUTY_CYCLE	Output Clock Duty Cycle (Measured at Cross Point)		48	50	52	%
t _R	Output Rise Time (20% and 80%)			250	400	ps
t _F	Output Fall Time (80% and 20%)			250	400	ps
t _{start}	Start-up Time			1	5	ms
	Aging	1 st Year			3	ppm
		Every Year After 1 st			1	ppm

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

3. Measurement taken with outputs terminated with 50 Ω to V_DD – 2.0 V. See Figure 4.

4. Parameter guarantees 10 years of aging. Includes initial stability at 25°C, shock, vibration, and first year aging.

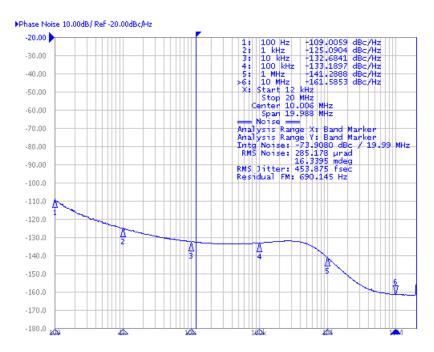


Figure 3. Typical Phase Noise Plot

Table 7. RELIABILITY COMPLIANCE

Parameter	Standard	Method
Shock	Mechanical	MIL-STD-833, Method 2002, Condition B
Solderability	Mechanical	MIL-STD-833, Method 2003
Vibration	Mechanical	MIL-STD-833, Method 2007, Condition A
Solvent Resistance	Mechanical	MIL-STD-202, Method 215
Thermal Shock	Environment	MIL-STD-833, Method 1011, Condition A
Moisture Level Sensitivity	Environment MSL1 260°C per IPC/JEDEC J-STD-020D	

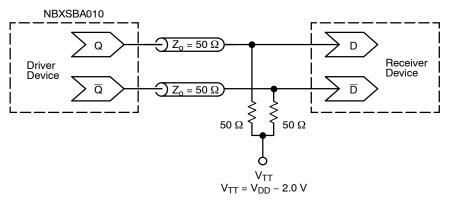


Figure 4. Typical Termination for Output Driver and Device Evaluation (See Application Note AND8020/D – Termination of ECL Logic Devices.)

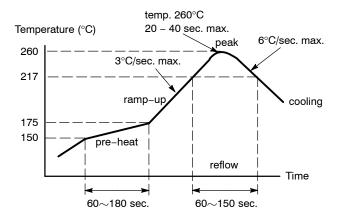
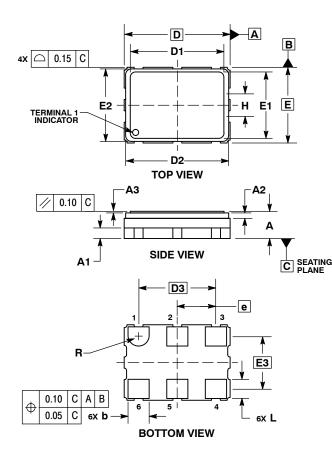


Figure 5. Recommended Reflow Soldering Profile

PACKAGE DIMENSIONS

6 PIN CLCC, 7x5, 2.54P CASE 848AB-01 ISSUE C

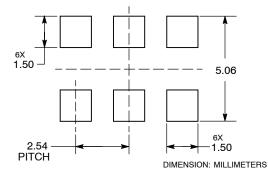


NOTES

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. 2. CONTROLLING DIMENSION: MILLIMETERS.

	MILLIMETERS			
DIM	MIN	NOM	MAX	
Α	1.70	1.80	1.90	
A1		0.70 REF		
A2		0.36 REF		
A3	0.08	0.10	0.12	
b	1.30	1.40	1.50	
D		7.00 BSC		
D1	6.17	6.20	6.23	
D2	6.66	6.81	6.96	
D3	5.08 BSC			
E		5.00 BSC		
E1	4.37	4.40	4.43	
E2	4.65	4.80	4.95	
E3		3.49 BSC		
е		2.54 BSC		
н		1.80 REF		
L	1.17	1.27	1.37	
R		0.70 REF		

SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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